



# Optane Summer Research 2022

Christopher, Arda, Caleb



# 10meter Data

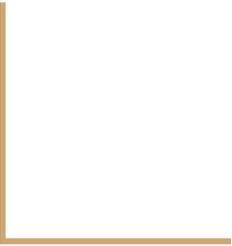


# Procedure

- Using IOmeter software, designed 64 tests starting at 512 B and doubling the request size until 16 MB for sequential r/w, random r/w
- Completed these 64 tests for at least 3 runs to calculate median value
  - Runs with high RSE were redone for more precise data
- Typed data on spreadsheet
- Organized data to make graphs to see how IOPS, MB/s, and response time changed with request size

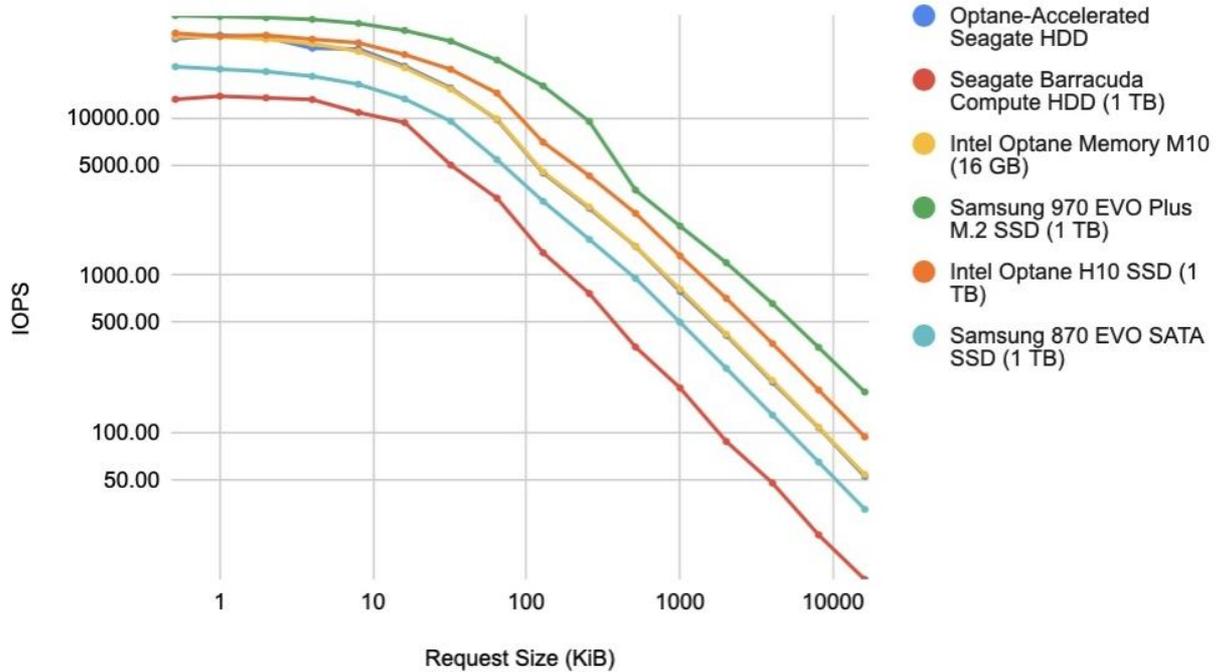


Sequential Read



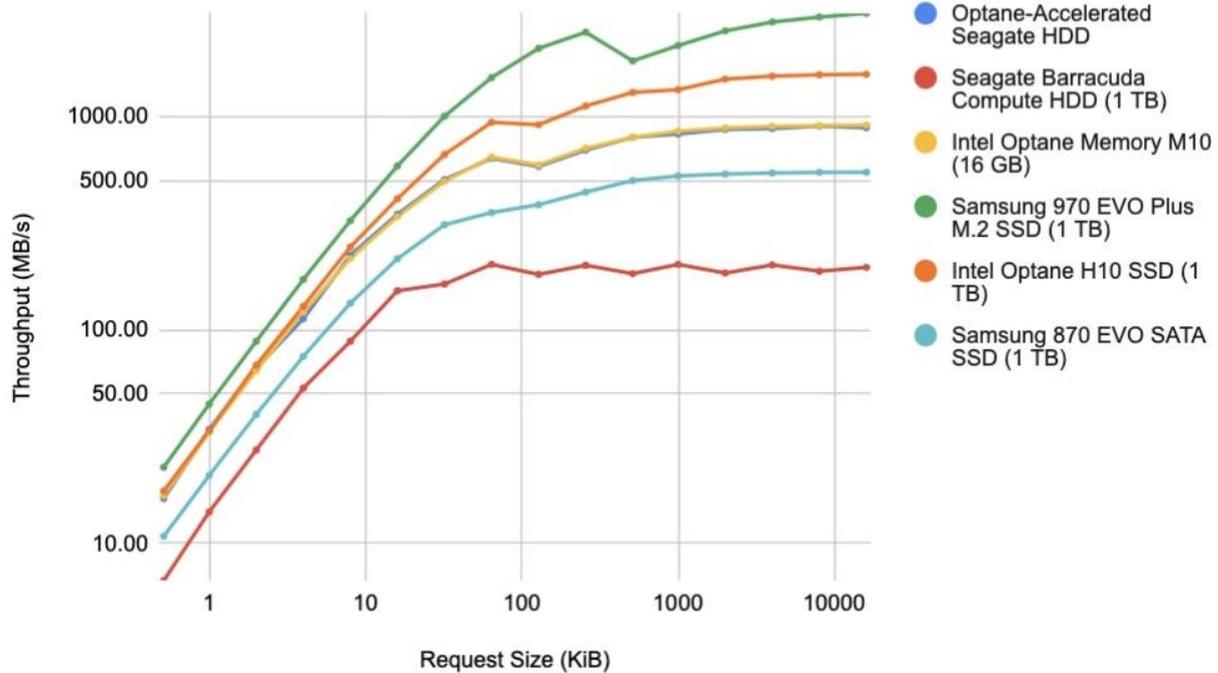
# IOPS

Sequential Read, IOPS



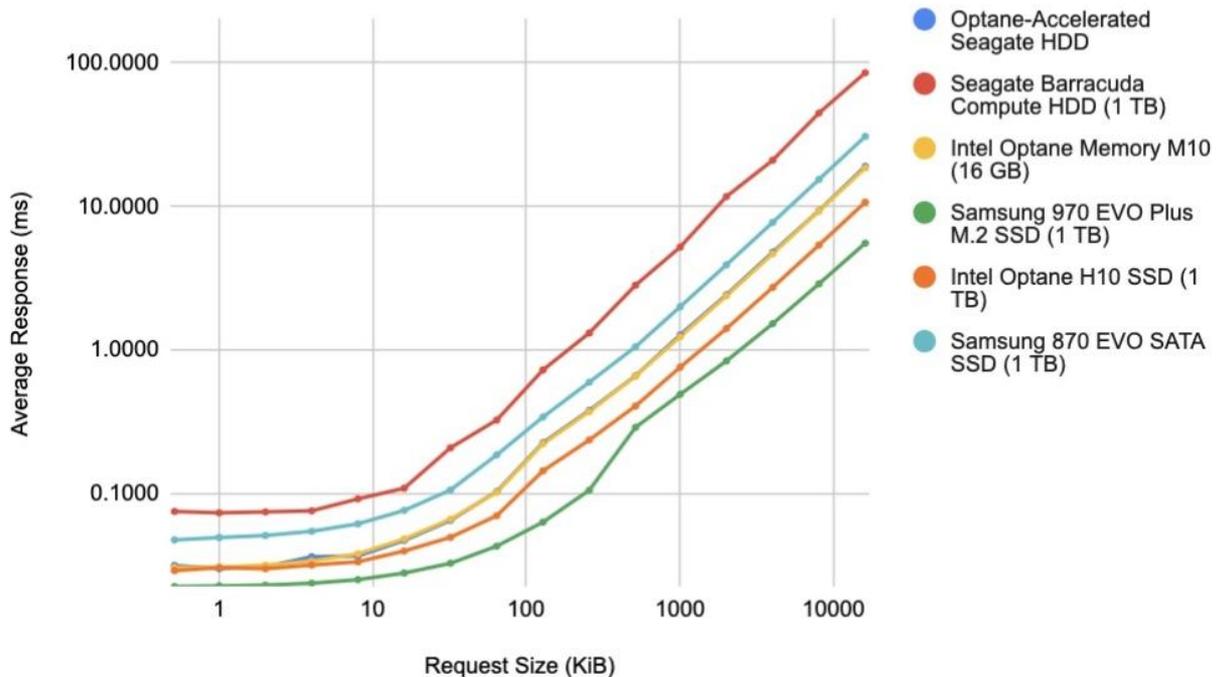
# MB/s

## Sequential Read, MB/s



# Latency

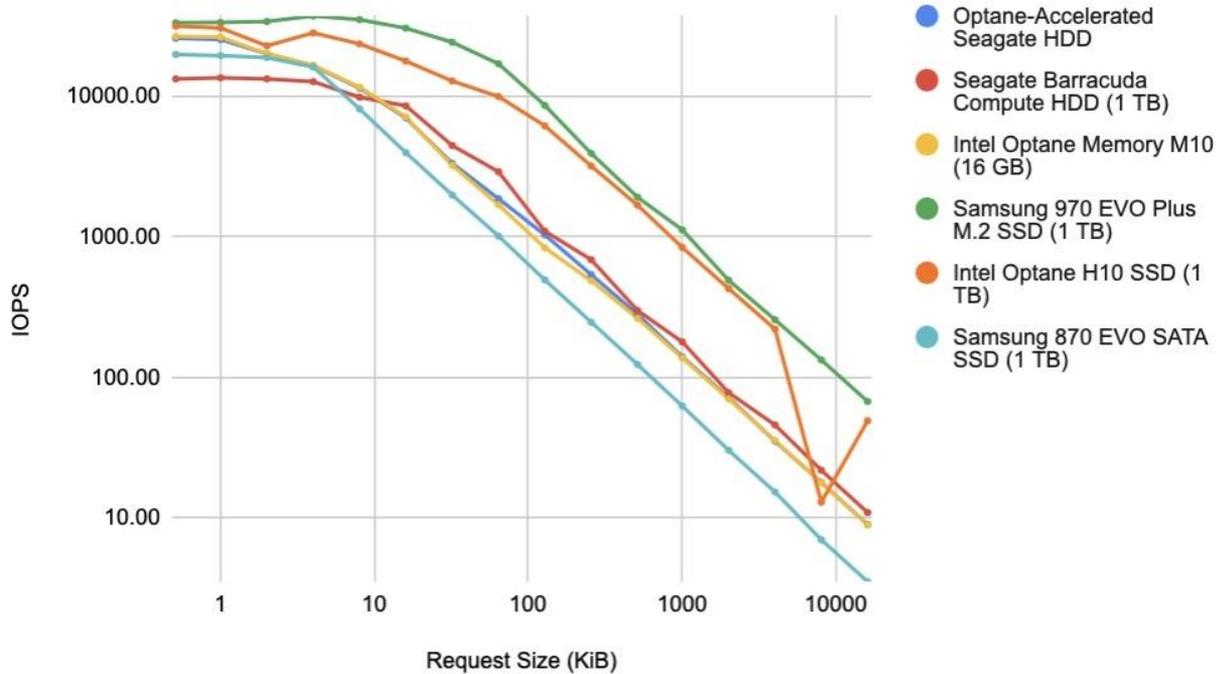
Sequential Read, Average I/O Response



# Sequential Write

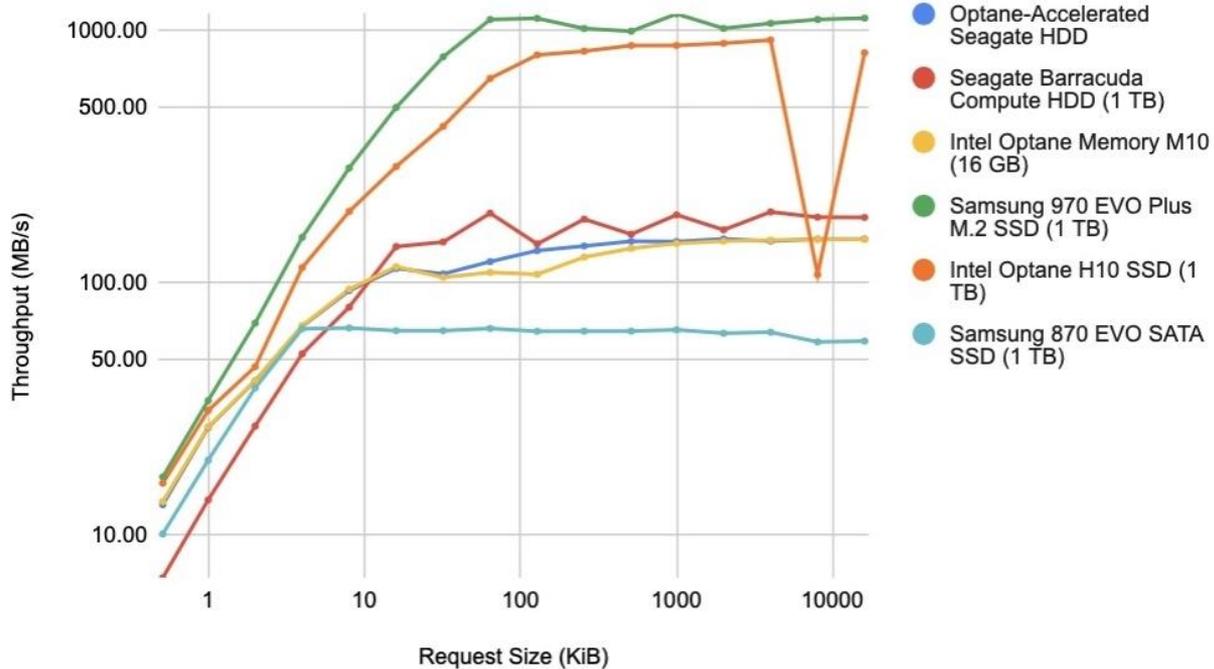
# IOPS

Sequential Write, IOPS



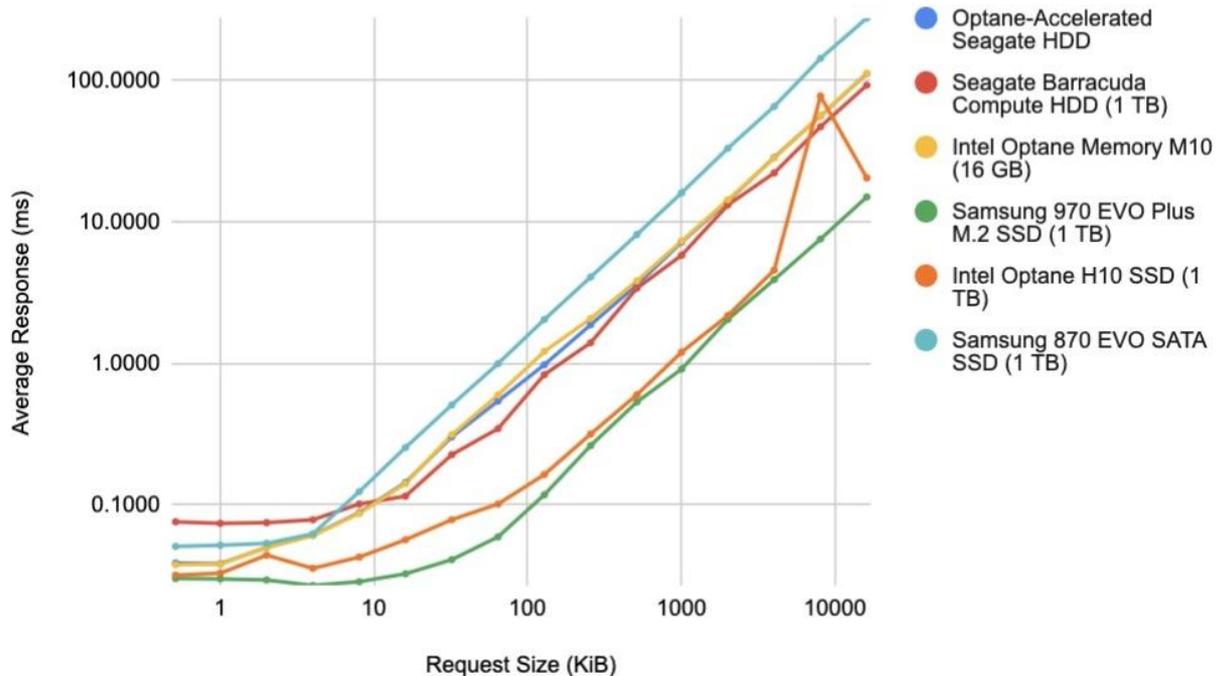
# MB/s

## Sequential Write, MB/s



# Latency

Sequential Write, Average I/O Response



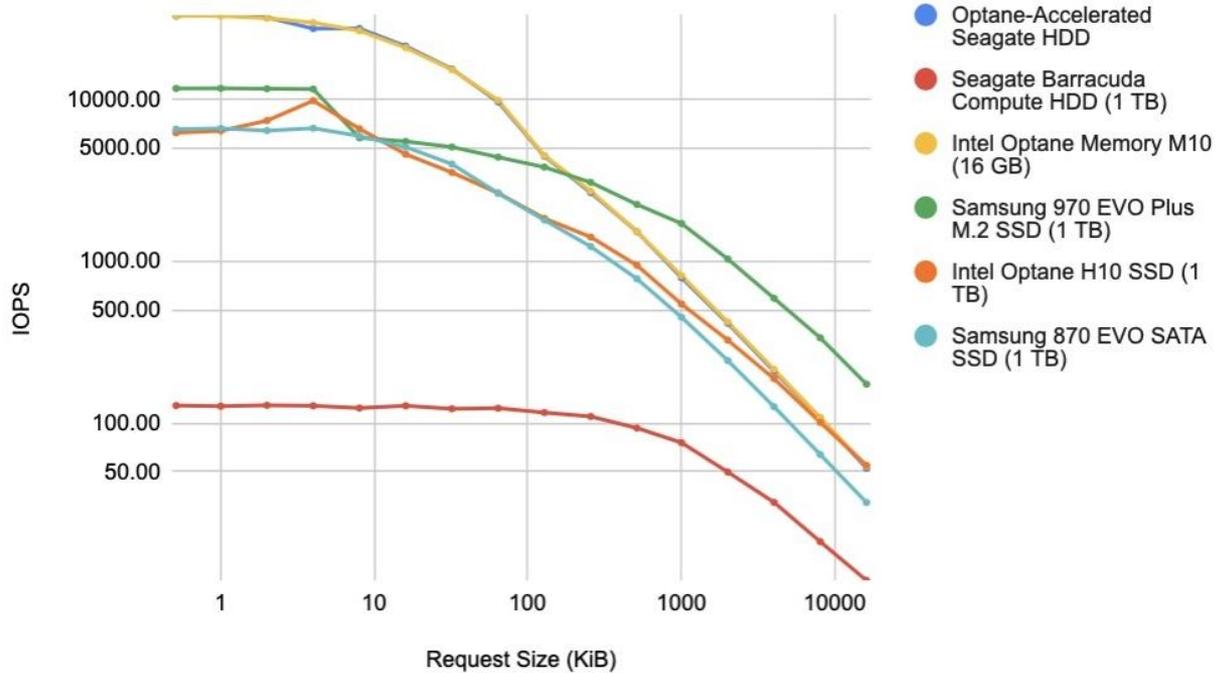


Random Read



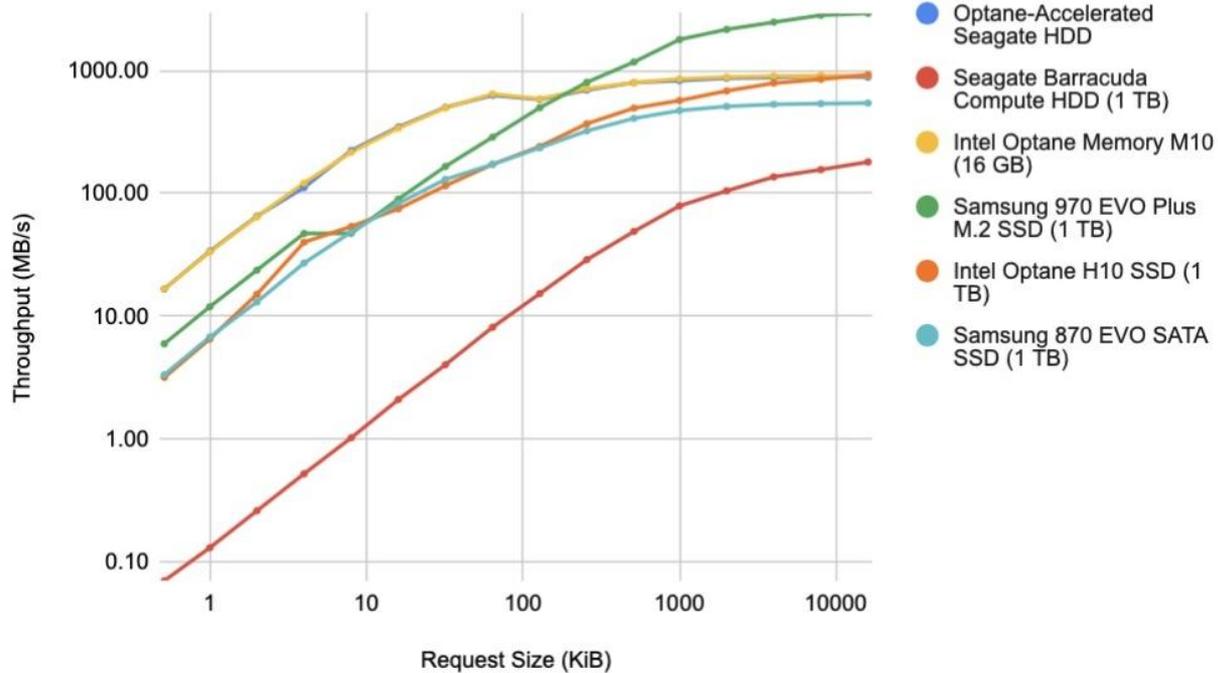
# IOPS

Random Read, IOPS



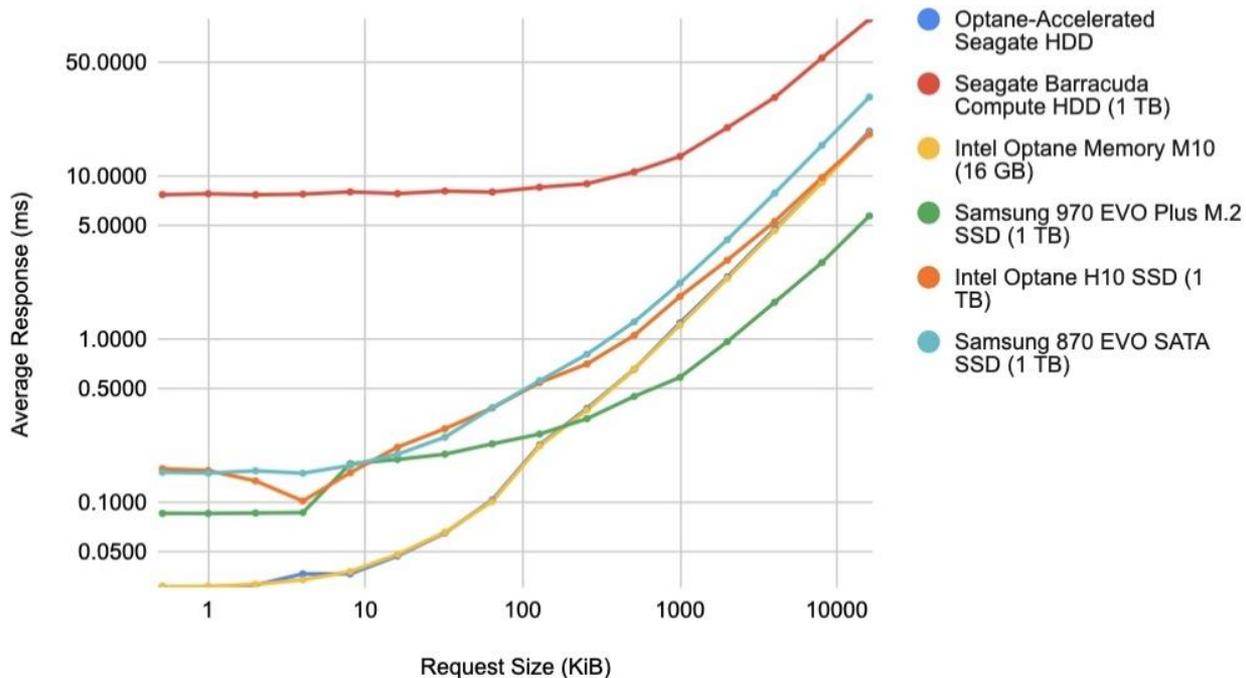
# MB/s

## Random Read, MB/s



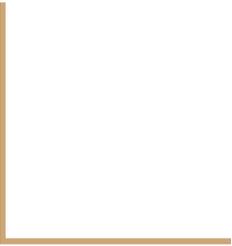
# Latency

Random Read, Average I/O Response



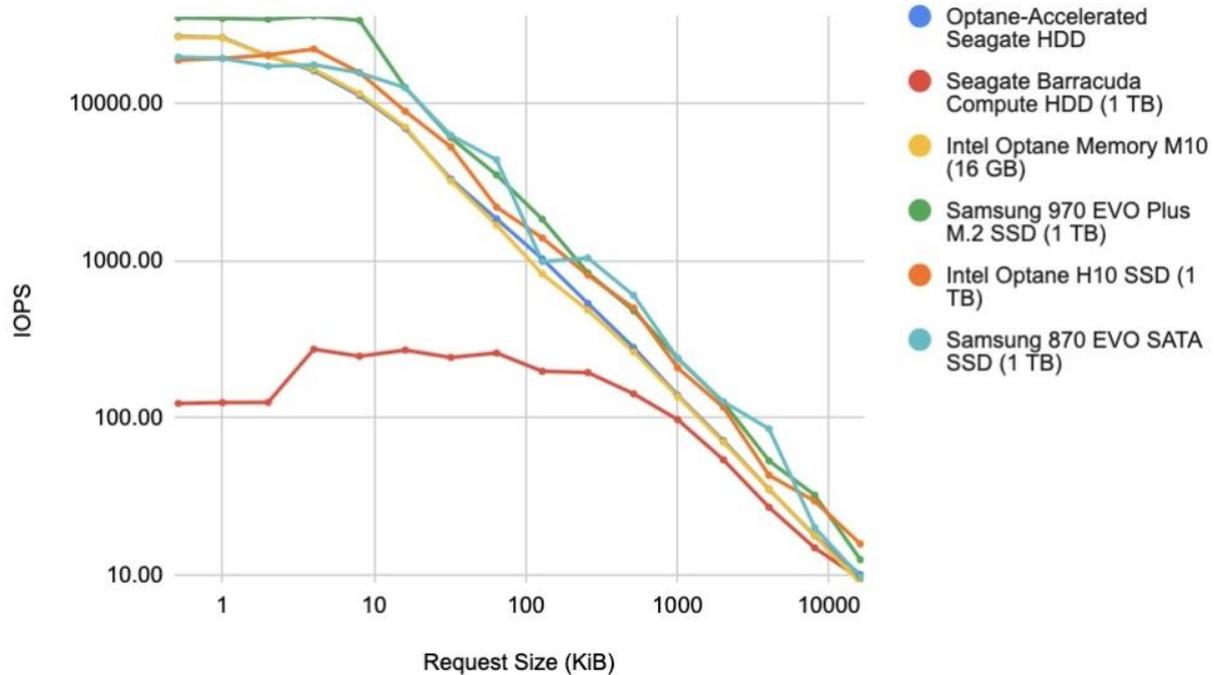


Random Write



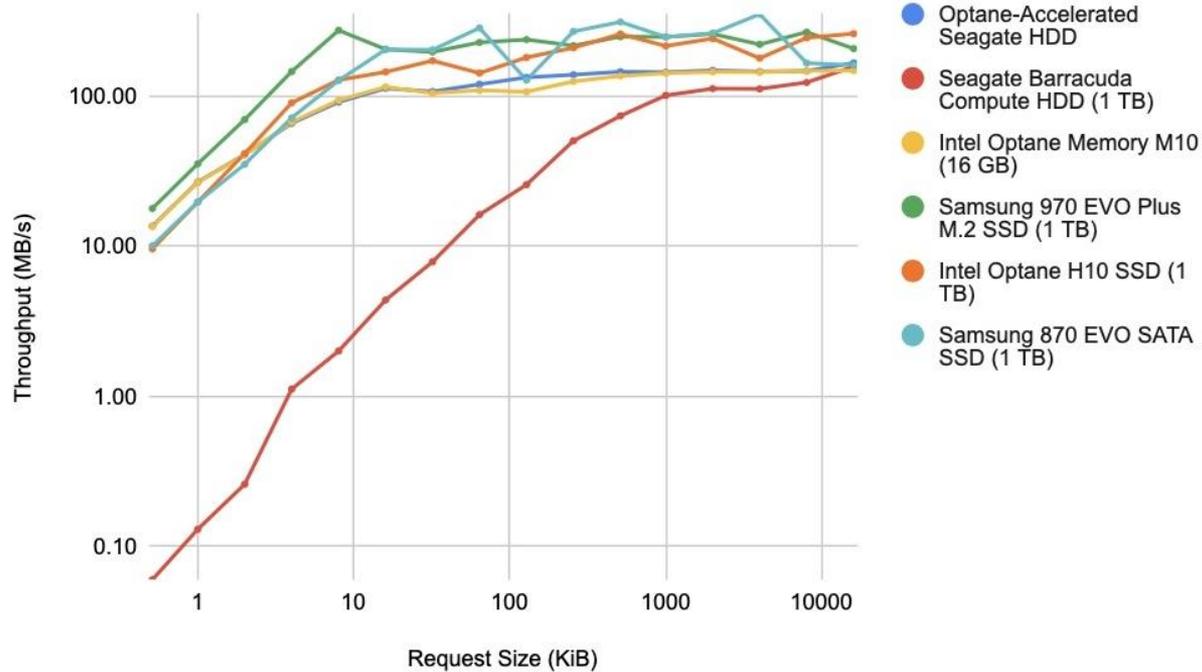
# IOPS

Random Write, IOPS



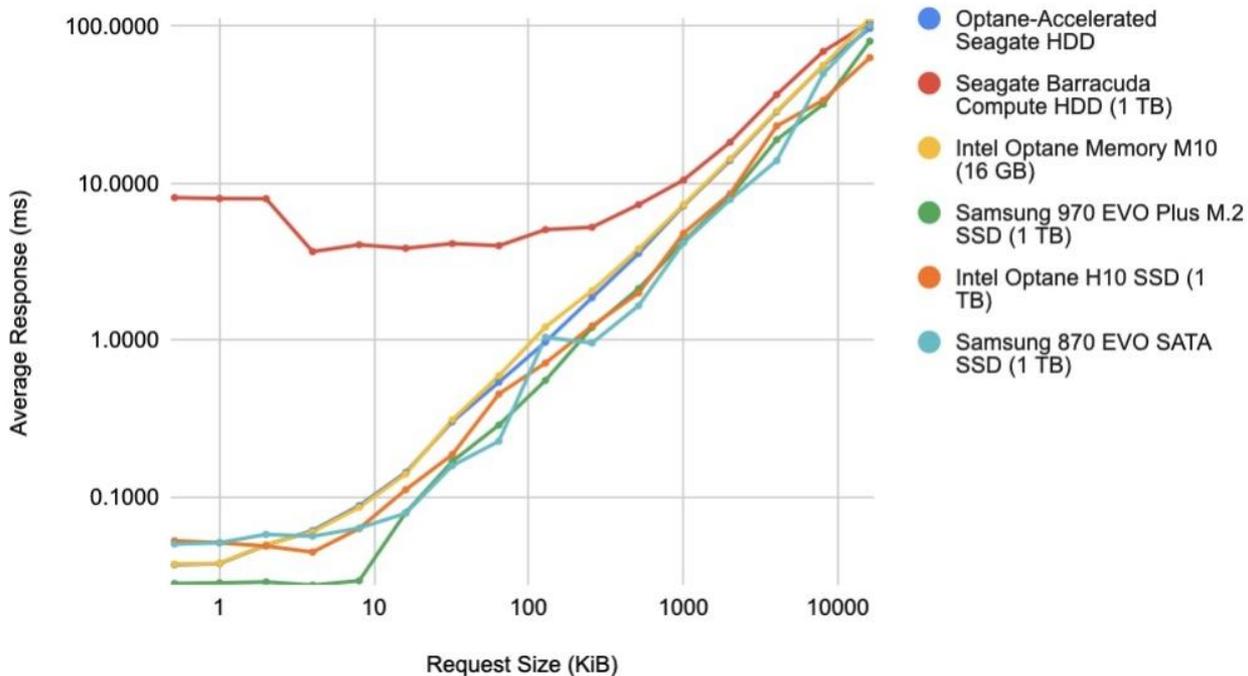
# MB/s

## Random Write, MB/s

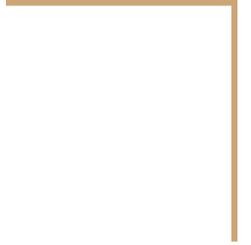


# Latency

Random Write, Average I/O Response



# Relative Standard Error

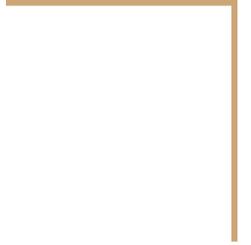


# RSE

Takeaway: Optane offered much more stability in performance than any other device

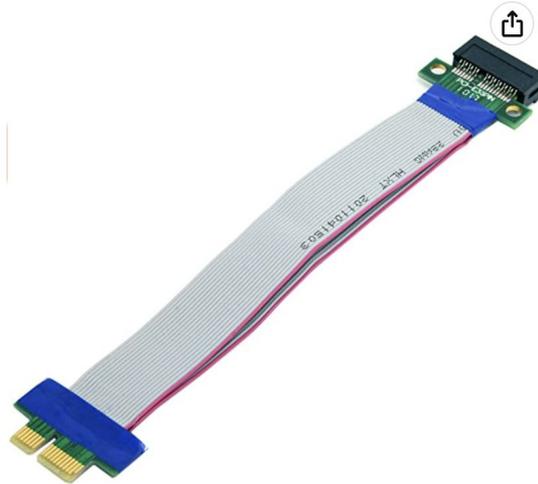
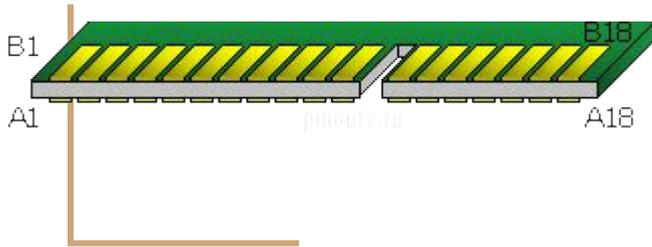


# Power Consumption Data



# Procedure

- found the corresponding voltage power lines
- discovered that the 12V power lines had no current
- cut open corresponding wires on riser cable
- connected to 10 Ohm resistor
- measured Voltage



Pin #	Side B Connector		Side A Connector	
	Name	Description	Name	Description
1	+12v	+12 volt power	PRSENT#1	Hot plug presence detect
2	+12v	+12 volt power	+12v	+12 volt power
3	+12v	+12 volt power	+12v	+12 volt power
4	GND	Ground	GND	Ground
5	SMCLK	SMBus clock	JTAG2	TCK
6	SMDAT	SMBus data	JTAG3	TDI
7	GND	Ground	JTAG4	TDO
8	+3.3v	+3.3 volt power	JTAG5	TMS
9	JTAG1	+TRST#	+3.3v	+3.3 volt power
10	3.3Vaux	3.3v volt power	+3.3v	+3.3 volt power
11	WAKE#	Link Reactivation	PERST#	PCI-Express Reset signal
Mechanical Key				
12	RSVD	Reserved	GND	Ground
13	GND	Ground	REFCLK+	Reference Clock Differential pair
14	HSOp(0)	Transmitter Lane 0, Differential pair	REFCLK-	
15	HSOn(0)		GND	Ground
16	GND	Ground	HSIp(0)	Receiver Lane 0, Differential pair
17	PRSENT#2	Hotplug detect	HSIn(0)	
18	GND	Ground	GND	Ground

# Results

- Measured across Wire 9 on Side A

Settings	Voltage	Power
Idle	7.6 mV	2.508 mW
Read	22.5 mV +- 2 mV	7.425 mW
Write	30 mV +- 5 mV	9.9 mW

$$I_{\text{measured}} = V_{\text{measured}} / (10 \Omega)$$

$$P = (3.3 \text{ V}) (I_{\text{measured}})$$

NOTE: I was only able to measure across one of the four power wires



# Limitations of Phase Change Memory

How Does Optane Operate Under  
Non-Ideal Conditions

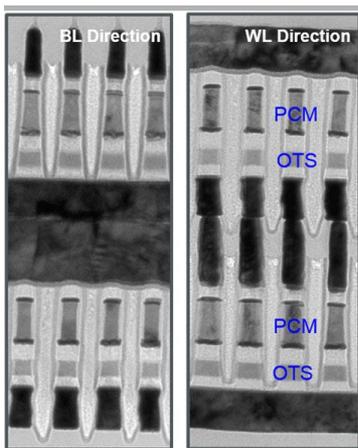


# Three Main Questions

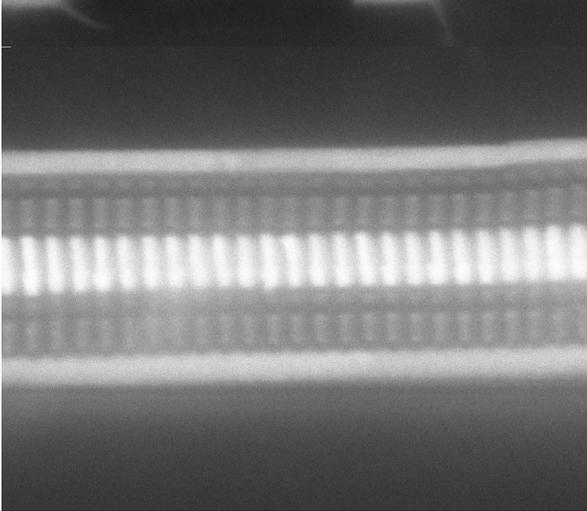
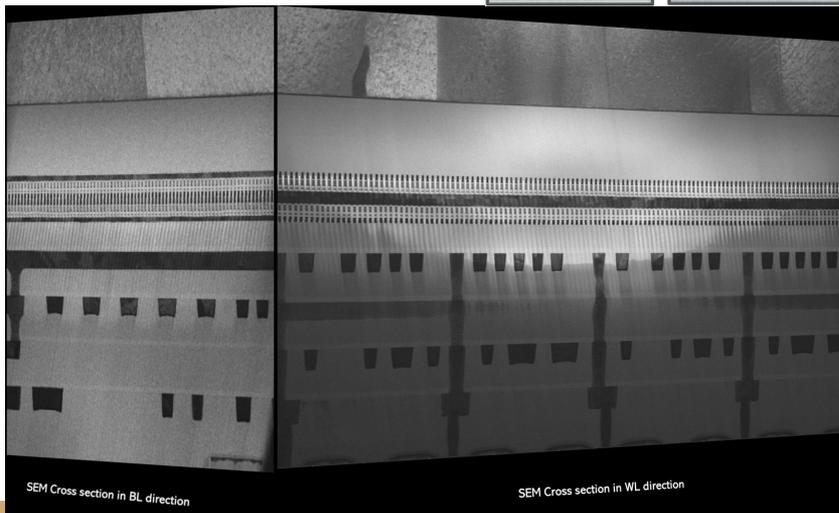
- How does the Chip Breakdown?
- When does the Chip Breakdown?
- Why is this Information Important?

# How Does Intel Optane Breakdown?

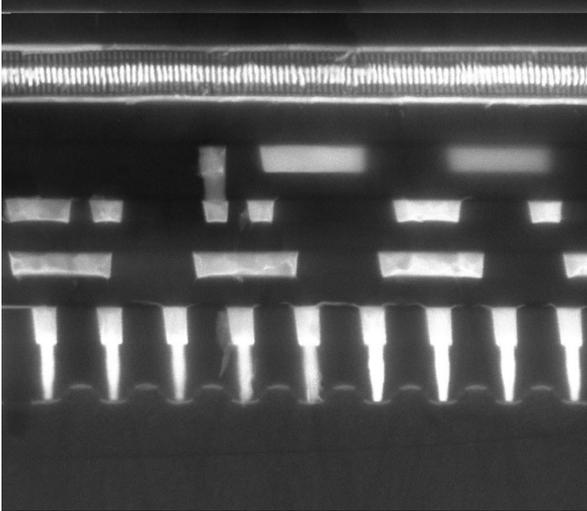
Cell Structure →



Overall Structure ↓

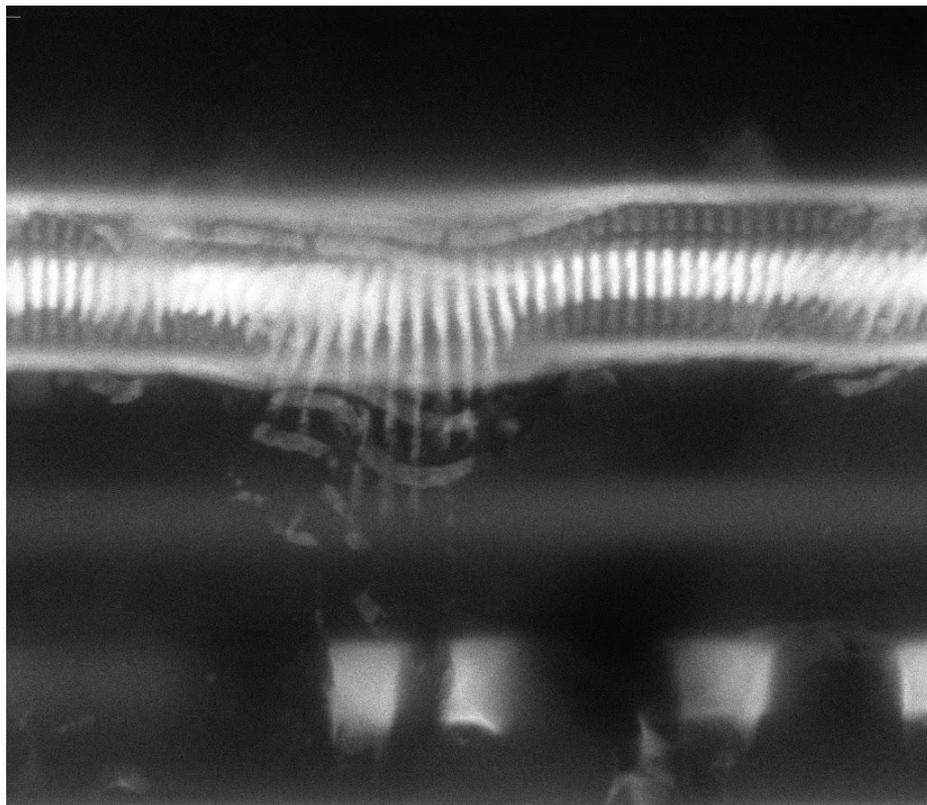


HV	spot	WD	mag	det	dwell	
30.00 kV	2.0	5.9 mm	119 999 x	BSED	30 $\mu$ s	400 nm



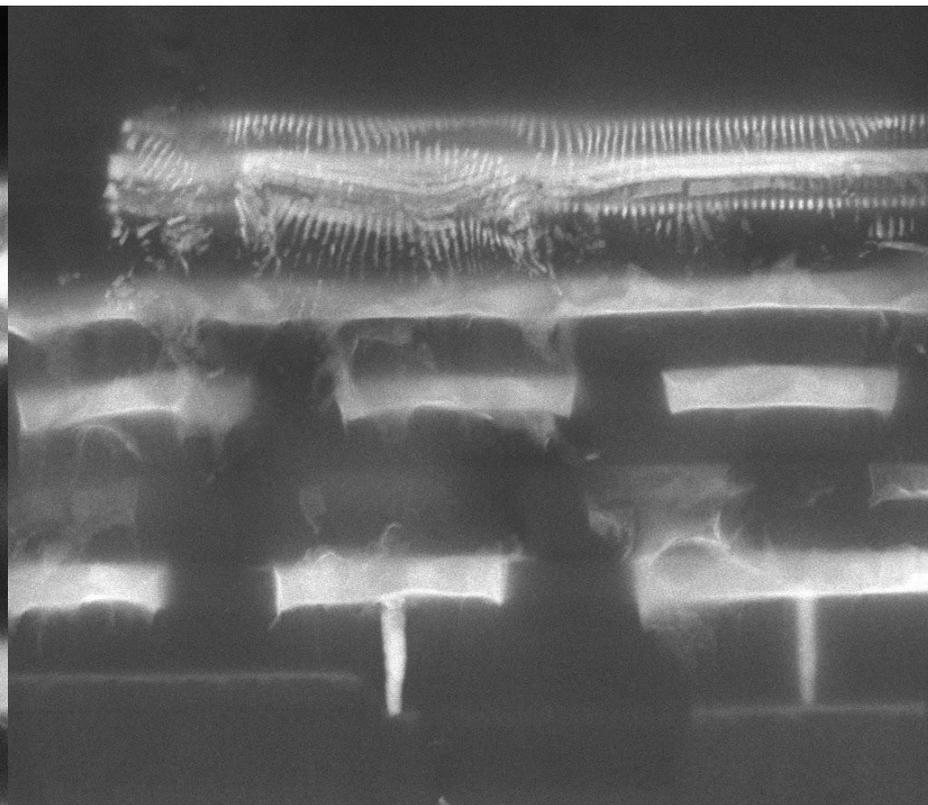
HV	spot	WD	mag	det	dwell	
25.00 kV	3.0	6.2 mm	30 000 x	BSED	30 $\mu$ s	1 $\mu$ m

# How Does Intel Optane Breakdown?



HV	spot	WD	mag	det	dwell
30.00 kV	2.5	6.0 mm	60 000 x	BSED	30 $\mu$ s

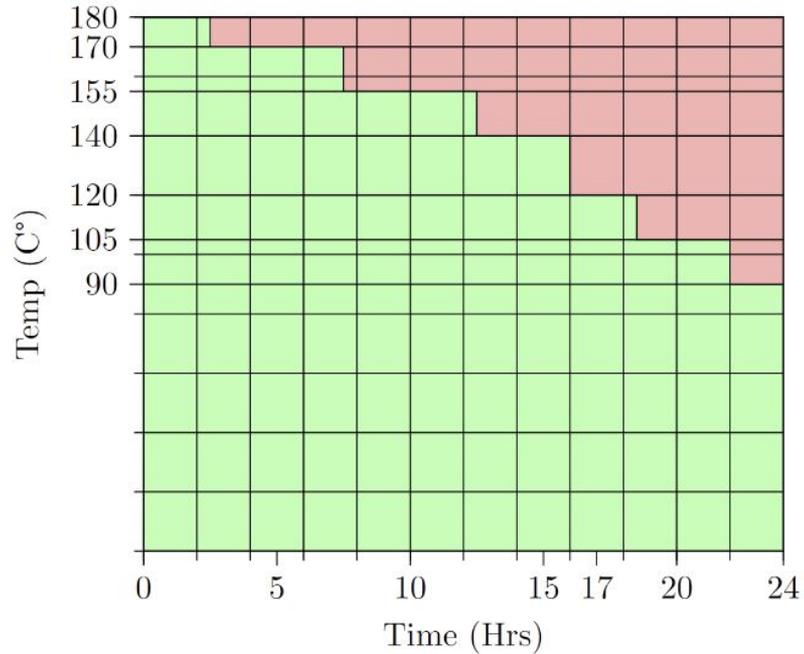
500 nm



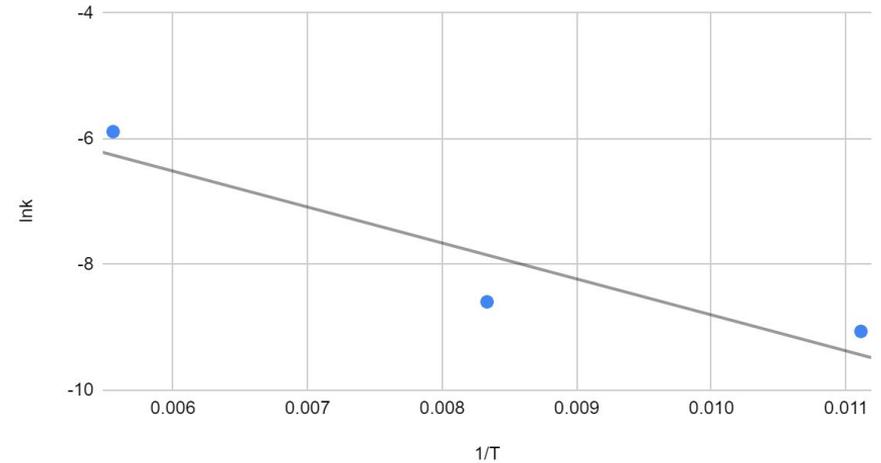
HV	spot	WD	mag	det	dwell
30.00 kV	3.0	5.9 mm	30 000 x	BSED	10 $\mu$ s

1  $\mu$ m

# When Does Intel Optane Breakdown?



Arrhenius Plot Of Optane Failure



<b>Non-GAAP adjustment or measure</b>	<b>Definition</b>	<b>Usefulness to management and investors</b>
Optane inventory impairment	In Q2 2022, we initiated the winding down of our Intel Optane memory business.	We exclude these impairments for purposes of calculating certain non-GAAP measures because these charges do not reflect our current operating performance. This adjustment facilitates a useful evaluation of our current operating performance and comparisons to past operating results.

(Image credit: Intel)

“The company will not develop any further generations, instead now taking a \$559m inventory write-off”

# Relevance of Optane Failure

- Not competitive (under ideal conditions)
  - Intel shut it down after millions of dollars and decades of time
  - Its slow (1 orders of magnitude slower)
  - Its high power (another 2 orders of magnitude higher)
- What happens when pushing it into conditions other memories don't want to go to
  - Theoretically could survive higher temperatures especially because can change crystallization temp of phase change material
  - If it could, would save data centers a lot of money in cooling power
    - Currently can't
  - Space, Cars

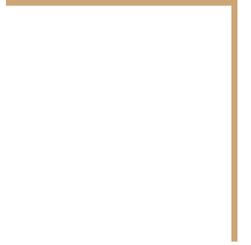
# Next Steps



# Next Steps

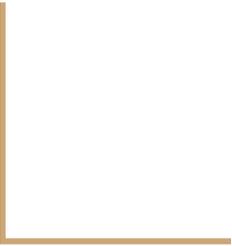
- Collect data from Optane/SATA SSD accelerated setup
  - Expect to have similar data as Optane/HDD accelerated setup, maybe similar to Optane SSD data
- Design PCB testing board with current-sense amplifiers for more accurate power consumption measurements (started, not finished)
- Get the development board
- Find failure points to know mean error time at a given temperature

Questions?

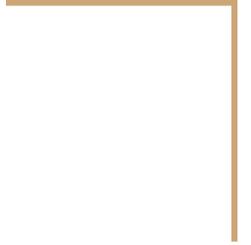


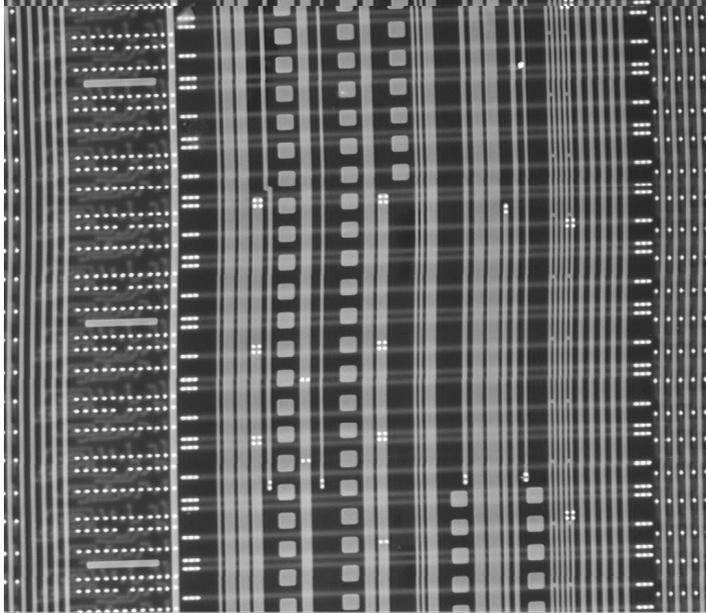


Thank You For Our Instructive Summer!

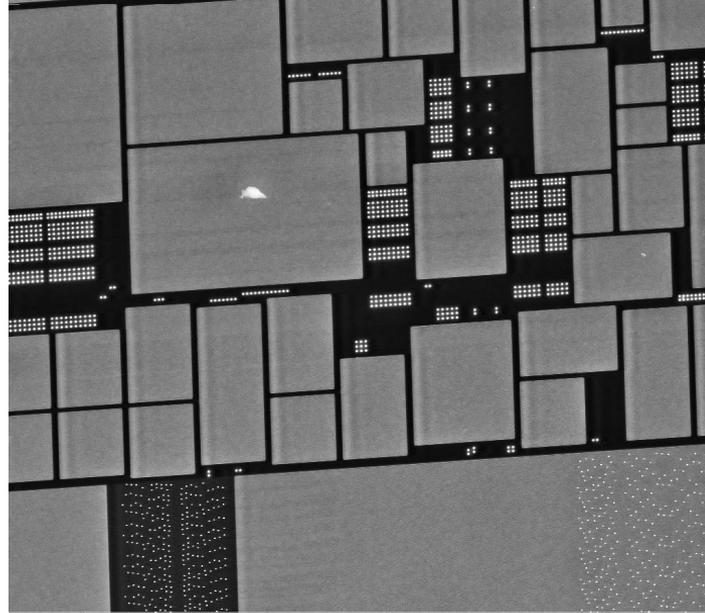


# SEM Images

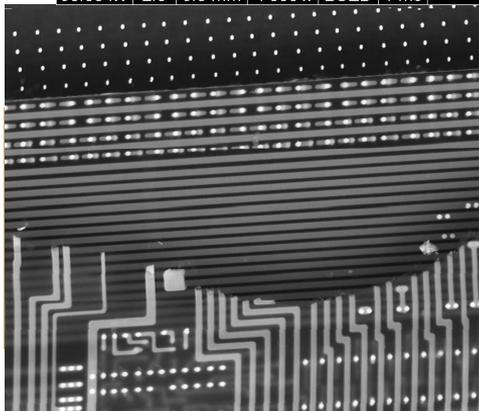




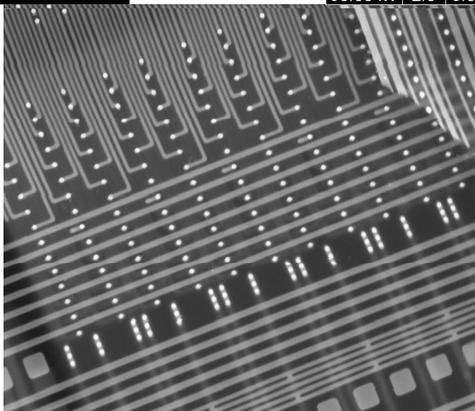
HV	spot	WD	mag	det	dwell	
30.00 kV	2.0	5.8 mm	4 000 x	BSED	1 ms	10 μm



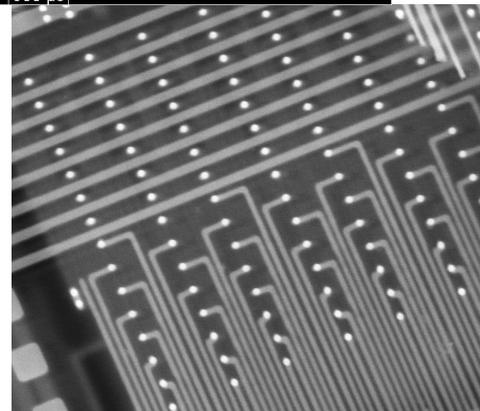
HV	spot	WD	mag	det	dwell	
30.00 kV	2.0	5.8 mm	2 000 x	BSED	300 μs	20 μm



HV	spot	WD	mag	det	dwell	
30.00 kV	2.0	5.8 mm	8 000 x	BSED	1 ms	5 μm



HV	spot	WD	mag	det	dwell	
30.00 kV	2.0	5.8 mm	8 000 x	BSED	1 ms	5 μm



HV	spot	WD	mag	det	dwell	
30.00 kV	2.0	5.8 mm	12 000 x	BSED	100 μs	4 μm